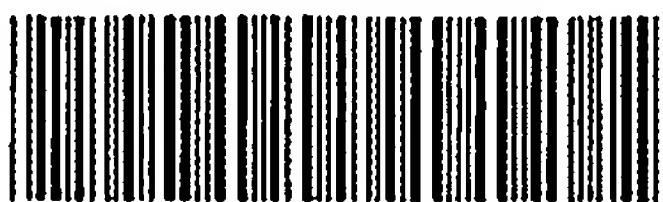


**Search Notes****Application/Control No.**

10/651,663

**Examiner**

Yuwen Pan

**Applicant(s)/Patent under Reexamination**

XIE, FEI

**Art Unit**

2682

**SEARCHED**

Class	Subclass	Date	Examiner
465	412.1 412.2 550.1	10/12/05	yw
	556.2		
707	205		
704	210	4/18/06	yw
	211		
	207		
	208		
	209		
	217		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Lewis West	10/12/05	yw
han, Qi	4/18/06	yw

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner